PCN Number:		20150219001						PCN	Date:	2/24/2015	
Title: Qualification of					of TI Mexico as a new Assembly and Test site for select PIP Module Devices						
Customer Contact:			PCN Manager			Dept:	Quality Services				
Proposed 1 st Ship Da			te: 05/24/2015			Estimated Sample Availab			ailability:	ty: Provided upon Request	
Cha	ange	Туре:									
\boxtimes	Asse	mbly Site		Assembly Process			Assembly Materials				
	Desi	gn			Electrical Specification			Mechanic	al Specif	ication	
	Test				Packing/Shipping/Labeling Te				Test Proc	ess	
	Wafer Bump Site Wafer Bur			Wafer Bur				Wafer Bump Process			
	Wafer Fab Site				Wafer Fab Materials V				Wafer Fab Process		
				Part number change							
						PCN De	etails				
Description of Change:											
Texas Instruments is pleased to announce the qualification of TI Mexico as a new Assembly and test site for the list of PIP devices shown below. There are no differences in the package construction as a result of this change. Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.											
Reason for Change:											
Continuity of Supply											
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):											
ıoN	None										

Changes to product identification resulting from this PCN: Assembly Site

Hana Thailand Assembly Site Origin (22L) ASO: HNT

TI Mexico Assembly Site Origin (22L) ASO: PTM

Sample product shipping label (not actual product label)





(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$I2 (P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Topside Device marking:

Assembly site code for HNT= H
Assembly site code for MEX= V

Product Affected							
PTR08060WVC	PTR08060WVD	PTR08100WVC	PTR08100WVD				

Qualification Data: Approved February 2014						
This qualification has been specifically developed for the validation of this change. The qualification data						
validates that the proposed chang	validates that the proposed change meets the applicable released technical specifications.					
Qualification Device: PTR08100WVD						
Package Construction Details						
Assembly Si	te: FMX A/T		Lead Finish:		Matte Sn	
# Pins-Designator, Fami	ly:	5-EDN, SIP MODULE				
Qualification: Plan Test Results						
Reliability Test		Conditions	Sample Size/Fail			
		Conditions	Lot#1	Lot#2		
Biased Power Cycled Life		6.6C Case Temp, 1000 H	40/0			
Biased Humidity	85C/85%RH, 1000 Hrs			40/0		
Vibration	MIL-STD-883D, 2007.2			9/0	9/0	
Mechanical Shock	MIL-STD-883D, 2007.3			3/0	3/0	

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com